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| FORM PTO-1449 US Dept. of Commerce Patent and Trademark Office | ATTORNEY DOCKET NO. 4173-101 | SERIAL NO. 09/884,791 |
| INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary) | | |
| APPLICANT David S. Kurtz, et al. | | |
| FILING DATE June 19, 2001 | | GROUP Z621 |

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| EXAMINER | DATE CONSIDERED 6-10-04 |
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